

Using the MSC121x as a High-Precision Intelligent Temperature Sensor

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ABSTRACT

The MSC121x [1] is an embedded controller with a high-precision, high-stability temperature sensor, a 24-bit delta-sigma ($\Delta\Sigma$) analog-to-digital converter (ADC), and an enhanced 8051 CPU. These circuit functions are the major building blocks for an intelligent temperature sensor. After temperature calibration, the on-chip temperature sensor measurement accuracy can reach $\pm 0.1^\circ\text{C}$ with a resolution of 0.01°C over an operating range of -40°C to 85°C . Applications for precision temperature measurements include, but are not limited to, thermocouple cold-junction-correction measurement, industrial process control, and system temperature monitoring. This article introduces the fundamental concept and operation of the on-chip temperature sensor. This report also describes the calibration procedures to turn the device into a high precision intelligent temperature sensor.

This application note uses the term *MSC121x* to refer to the MSC1210/MSC1211/MSC1212 as a series of devices.

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1 Temperature Sensing System

The MSC121x has an on-chip precision temperature sensor, 24-bit delta-sigma ADC, an 8-bit 8051 CPU, communication and input/output peripherals (Figure 1). These single chip-embedded functions can be used to compose a temperature sensing system for intelligent temperature monitoring, temperature measurements for IPC, or cold-junction-corrections. Usage examples for such temperature measurement results are:

- Provide feedback to other systems via communication peripherals
- Generate status and/or response to other control via input/output peripherals
- Provide temperature-logging record with 32KB Flash storage
- Detect system temperature drift to calibrate measurement offset and gain accuracy for external analog sources

The device communication peripherals include a variety of industrial standards: UART (dual), SPI™, and I²C™ (MSC1211 only).

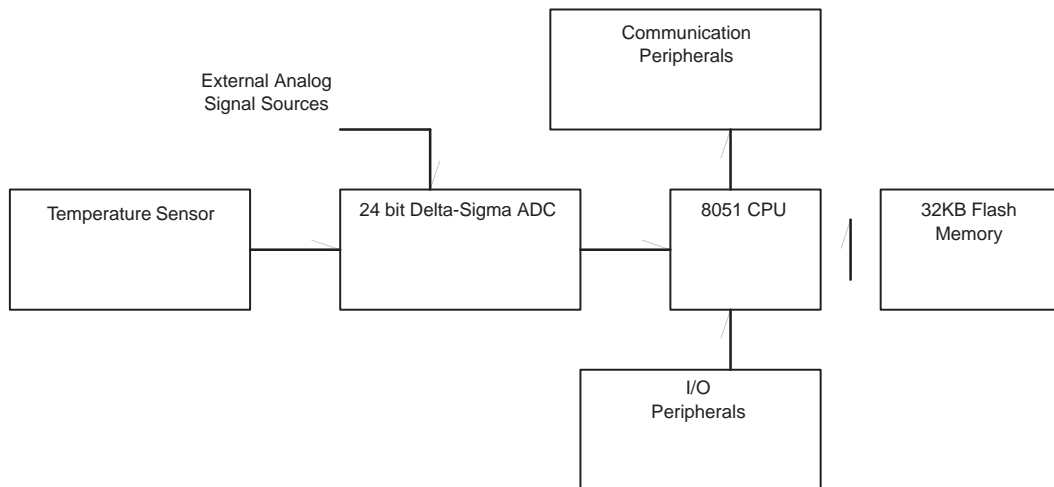


Figure 1. MSC121x Intelligent Temperature Sensor

1.1 Temperature Sensor Circuit

The MSC121x has a pair of temperature sensing diodes D1 and D2, as shown in Figure 2. The differential inputs of the on-chip ADC converter are selectable via input multiplexers. When the ADC multiplexer control (SFR ADMUX) is set to FF_H, the ADC inputs are connected to the temperature diode outputs. The differential voltage of the diode pair provides a temperature reading.

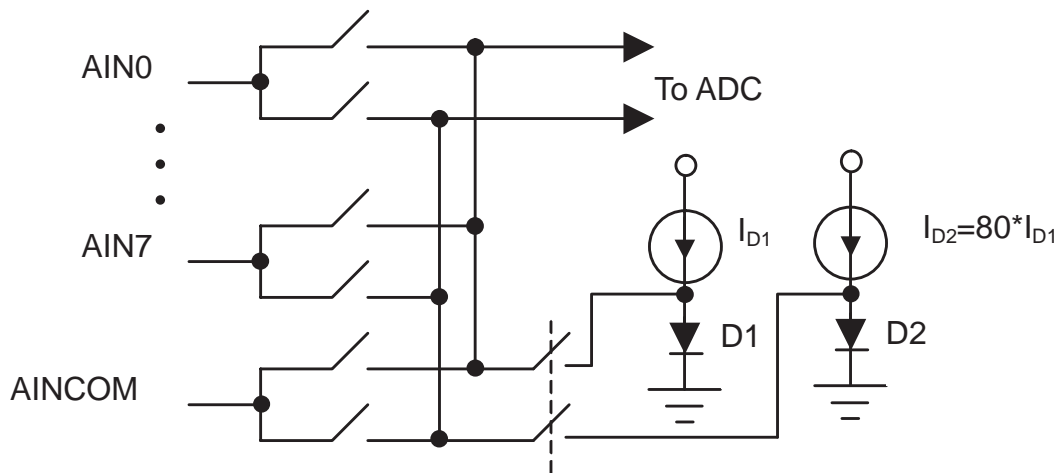


Figure 2. Block Diagram of Temperature Sensor

1.2 Temperature Sensor Parameters

The theory of using a silicon diode to measure temperature is discussed in the TI Application Report, *Measuring Temperature with the ADS1216, ADS1217, or ADS1218* [2]. Most of the discussion from this bulletin applies to the MSC121x design. Equation 1 shows the PN junction ideal diode equation. Table 1 shows the parameter description for the diode equation. In the MSC121x implementation, I_{DIODE} is from a constant current source. I_S is the only temperature-dependent parameter. To eliminate I_S , differential measurement is used.

$$V_{DIODE} = \frac{nkT}{q} \ln\left(\frac{I_{DIODE}}{I_S}\right)$$

Equation 1. Ideal Diode Equation

Parameters	Descriptions
V_{DIODE}	Diode voltage
n	Diode emission coefficient (typical value = 1)
k	Boltzman constant = $1.3806503E-23$ J/ °K
T	Absolution Temperature (°K)
q	Charge of an electron = $1.602176462E-19$ C
I_{DIODE}	Diode current
I_S	Diode saturation current (function of diode design and temperature)

Table 1. Diode Equation Parameters

The diode voltages for D1 and D2 in Figure 2 are V_{D1} and V_{D2} , respectively. The difference of the diode voltages is V_{temp} . The constant current applied to the diodes, I_{D1} and I_{D2} , is designed such that $I_{D2} = 80 \cdot I_{D1}$. The two diodes are also designed such that diode saturation currents, I_S , of the two diodes are identical. Identical I_S are achieved by closely matching the two diode feature sizes and applying silicon layout techniques to reduce process variation for components on the same silicon die. Therefore, as shown in Equation 2, the diode pair output voltage V_{temp} is proportional to the absolute temperature T, where α is a temperature-independent constant.

$$V_{temp} = V_{D1} - V_{D2} = \frac{nkT}{q} \left[\ln\left(\frac{I_{D1}}{I_S}\right) - \ln\left(\frac{I_{D2}}{I_S}\right) \right] = \frac{nkT}{q} \ln\left(\frac{I_{D1}}{I_{D2}}\right) = \alpha T$$

Equation 2. Differential Diode Equation

The MSC121x device V_{temp} measurement results do not exactly match with Equation 2. Examples for the sources of deviation from Equation 2 are:

- Diode emission coefficient, n, in Equation 1 is a function of I_{DIODE} ; therefore, the assumption that n equals 1 should be corrected
- Perfectly matching D1 and D2 is not possible; therefore, the saturation currents (I_S) of D1 and D2 are not identical

- The ratio of I_{D1} and I_{D2} is not temperature-independent; therefore, when the diode pair differential voltage is calculated from the temperature in Equation 2, the resulting voltage has a high-order term of T (for example, $V_{temp} = aT^2 + bT + c$).
- The ratio of I_{D1} and I_{D2} is not identical across each device; therefore, a single α value cannot be used for all devices
- The coefficients are calibrated to the temperature range of interest; thus, extrapolation beyond this range will result in error. For instance, when $T = 0^\circ\text{K}$, the voltage is not equal to zero.

1.3 Ideal Diode Equation

$$V_{temp} = \frac{nk \ln(80)}{q} (T_c + 273.15) = mT_c + c$$

Equation 3. Linear Temperature Equation

	Slope Coefficient m ($\mu\text{V}/^\circ\text{C}$)	Intercept Coefficient c (mV)	Curve Fitting Accuracy ($^\circ\text{C}$)	System Accuracy ($^\circ\text{C}$)
Ideal Diode	$nk \ln(80)/q = 377.6$	$m \cdot 273.15 = 103.1$	NA	NA
Linear Curve Fitted	386.7	104.98	+0.44/-0.30	+0.49/-0.35
Polynomial Curve Fitted	$V_{temp} = 6.3595E-5 T_c^2 + 0.3842 T_c + 104.90$		+0.045/-0.048	+0.095/-0.098

Table 2. Temperature Sensor Slope and Intercept Coefficients

Converting the voltage to temperature using a linear equation simplifies conversion computation. Equation 2 is rearranged to a linear format to give Equation 3. Following are characteristics of Equation 3:

- $^\circ\text{Celsius}$ is used instead of $^\circ\text{Kelvin}$ ($^\circ\text{Celsius} = ^\circ\text{Kelvin} - 273.15$)
- Constant current ratio between I_{D1} and I_{D2} equals 80
- T_c is the diode temperature in $^\circ\text{C}$
- m is the temperature slope coefficient
- c is the temperature intercept coefficient

The slope coefficient, m , and intercept, c , represent the gain and offset, respectively, of the temperature equation. When the constants of the ideal diode equation (Table 1) are used for Equation 3, coefficients for the ideal equation can be calculated. The values are shown in the *Ideal Diode* row of Table 2. For physical devices, m and c are different from the ideal values.

2 Temperature Sensor Accuracy

2.1 Linear Curve Fitting

To understand if the physical device measurement result is different from that generated by the ideal model, a linear curve fitting with least square method¹ is used. V_{temp} is measured for 15 temperature points² within the range of -40 to 85°C . V_{temp} results are shown on the left y-axis of Figure 3. The measurement points have a very linear distribution. The linear curve fitted coefficients are shown on the *Linear Curve Fitted* row of Table 2. The coefficients are within 2.5% of the ideal coefficients.

The linear curve fitted result also shows the precision of the temperature measurement system. When the curve fitted coefficients are used to calculate temperature from measured V_{temp} , the error of the system is shown on the line *Linear Err*, referencing the right-y-axis of Figure 3. The error of linear curve fitting is within $+0.44$ and -0.30°C .

System accuracy is defined as the measurement accuracy when the temperature range of interest is measured repeatedly with the curve fitting coefficients. The system accuracy result is listed in the last column of Table 2. The curve fitting precision is affected by the measurement equipment setup accuracy, reference temperature sensor specifications, and system uncertainties. The measurement equipment setup accuracy for this report is around $\pm 0.05^{\circ}\text{C}$. System accuracy using linear curve fitting is $\pm 0.5^{\circ}\text{C}$. This level of accuracy outperforms many precision temperature sensors and equipment.

Each device may have unique values of m and c . If enough measurement points of (V_{temp}, T_c) are acquired for each device, and the points are linear curve fitted, a system measurement accuracy of $\pm 0.5^{\circ}\text{C}$ should be achievable. In addition to high-precision measurement, another advantage of using linear curve fitting is low computation requirements, which need only one multiplication and one addition.

Computing T_c from V_{temp} is simply the inverse function of Equation 3:

$$T_c = \frac{V_{temp}}{m} - \frac{c}{m} = m'V_{temp} + c'$$

Equation 4. Linear Inverse Function of $V_{temp} = f(T_c)$

The coefficients m' and c' for Equation 4 could be calculated from m and c . Another possible method for calculating m and c is that instead of using temperature for x-axis and V_{temp} for y-axis (as in Figure 3), generating the linear curve fitting results again with x-axis as V_{temp} and y-axis as temperature.

¹ Microsoft Excel™ functions of regression are used for this report. See Microsoft Excel™ user's manual for details of regression usage.

² Measurement results table is listed in Appendix A.

When curve-fitting results are used to compute T_C from V_{temp} , this is the sensor calibration process. This calibration process eliminates offset (c) and gain (m) error in the complete signal chain. Example errors in the chain are interconnection offset, signal conditioning circuit gain/offset, ADC gain/offset, reference voltage accuracy/temperature draft, and silicon die-to-package temperature difference.

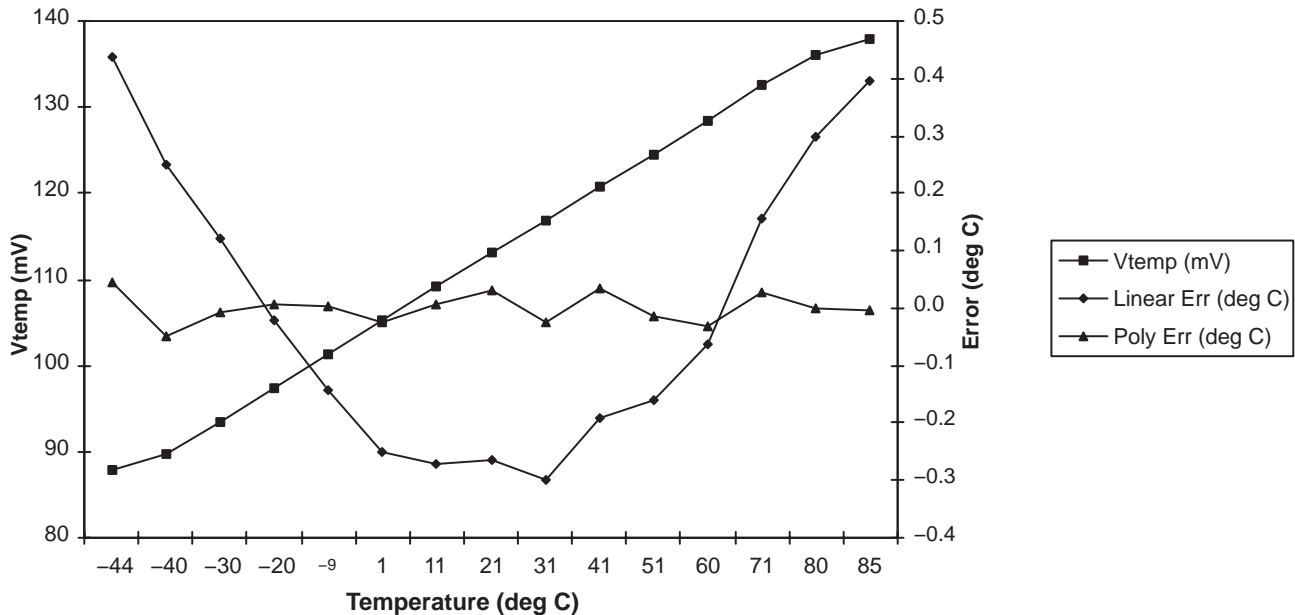


Figure 3. MSC V_{temp} (left y-axis) and Measurement Accuracy (right y-axis)

2.2 Polynomial Curve Fitting

The linear ideal equation, Equation 3, includes only a first-order effect from T_C . V_{temp} is actually a function of a higher-order effect of T_C . When the higher-order component of T_C is considered, a new level of temperature measurement accuracy can be achieved. The V_{temp} data points (Figure 3) are curve fitted with a second-order polynomial. The *Polynomial Curve Fitted* row of Table 2 shows the second-order polynomial and its coefficients. The error of temperature measurement that occurs when this polynomial is used appears on the *Poly Err* curve in Figure 3. The curve fitting error is reduced to $+0.045/-0.048^{\circ}\text{C}$ (an error range of 0.093°C), showing improvement over the linear curve fitting method by a factor of five. When measurement system error is considered, overall system accuracy of $\pm 0.1^{\circ}\text{C}$ can be achieved.

Inspecting the coefficient of the T_C^2 term in Table 2, this value is much smaller than the other two coefficients of the same equation. When third- or higher-order polynomial curve fittings for the 15 measurement points are used (see Appendix A), no significant curve fitting error reduction can be obtained. It can be seen that third-order polynomial curve fittings may slightly reduce measurement error. However, using a third-order polynomial increases computational requirements.

Equation 5 shows the inverse function of the second-order polynomial $V_{temp} = f(T_C)$ (Table 2). Equation 5 is useful to calculate T_C from the ADC-acquired voltage V_{temp} . Similar to the inverse function of the linear equation, the coefficients for this equation can be generated by using curve fitting with V_{temp} at the x-axis and T_C at the y-axis.

$$T_c = aV_{temp}^2 + bV_{temp} + c'$$

Equation 5. Second-Order Inverse Function of $V_{temp} = f(T_C)$

3 Temperature Sensor Calibration Methods

The curve fitting method is very effective for computing the linear or polynomial equation coefficients. This method requires measuring the (V_{temp} , T_C) points. The precision of the equation increases as more points are included. However, increasing measuring points increases equipment-manufacturing cost and complexity. Reducing the number of calibration measurement points is desired. Table 3 shows the summary of different level of calibration complexities.

Cal. Methods	Error Magnitude (°C)	Description
Zero Point (Non-calibrated)	6.5	Use averaged slope and intercept coefficient $m'_{ave} = 1/m_{ave} = 2582.173^\circ\text{C}/\text{V}$ $c'_{ave} = -c_{ave}/m_{ave} = -269.386^\circ\text{C}$
1 Point	2	Significant accuracy improvement with only one point calibration
2 Points	+0.62/-0.20, Worst case ± 1	Equation 3, 2 points at -10/+50°C
3 Points	Linear equ: +0.28/-0.54, worst case ± 0.7 Second-order equ: +0.07/-0.14, worst case $\pm 0.2^\circ\text{C}$	3 points at -40/+20/+85° C Second-order equ matching the accuracy as 15 pts calibrations
6 – 15 Points	± 0.1	6 points with third-order polynomial 15 points with second-order polynomial

Table 3. Temperature Sensor Calibration Complexities vs. Precision

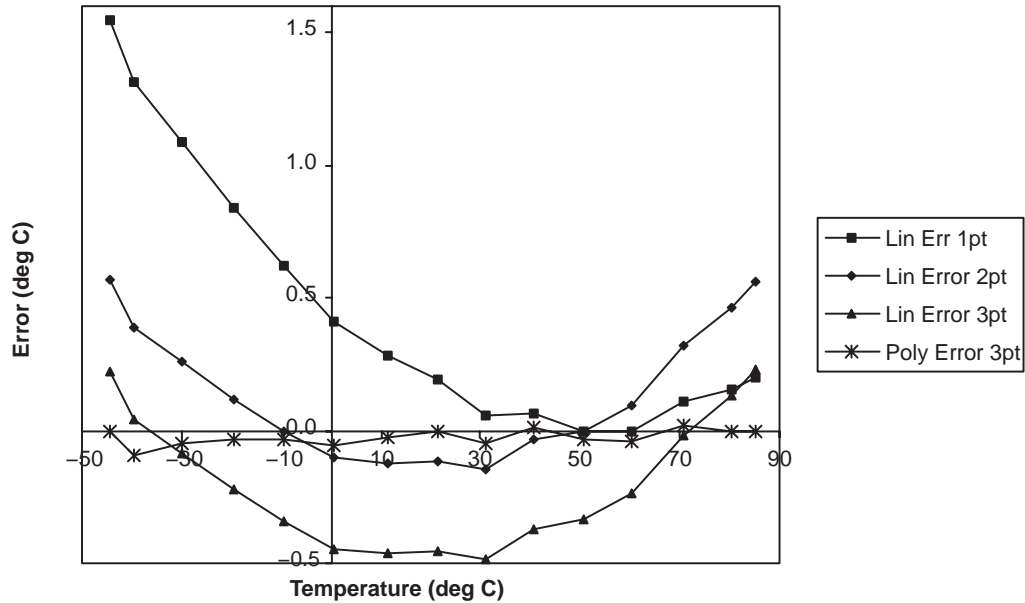


Figure 4. Increasing Accuracy with Calibration Complexity

3.1 Two Points Calibration

The linear equation, Equation 3, has two unknown coefficients, m and c . Two points are needed to solve for m and c . When solving the equation, an error in m will introduce gain error. An error in c will cause offset error. The *Linear Err* curve (Figure 3) is a parabola with the most negative error at the bottom of the curve and the most positive errors on the top two ends of the curve. The error at -10°C and $+50^{\circ}\text{C}$ have the minimum error. Using these two temperatures to calibrate the linear equation gives the lowest error. These calibration point selections give a measurement accuracy of $+0.6/-0.2^{\circ}\text{C}$ that is similar to multiple points' calibration (Table 3). The worst-case error would be lower than the peak-to-peak of the Figure 3 *Linear Err* curve that is less than 1°C .

3.2 Three Points Calibration

The worst-case error for second-order polynomial curve fitting would be lower than half of the peak-to-peak of the Figure 3 *Linear Err* curve that is less than 0.5°C , for most devices.

3.3 No Calibration and One Point Calibration

3.3.1 Average Coefficient Values

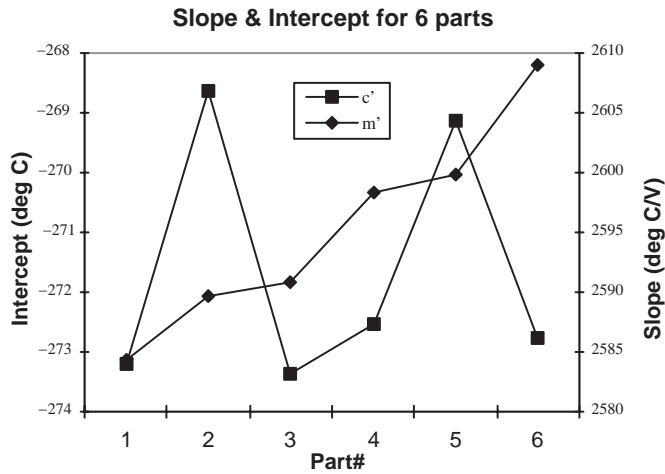


Figure 5. Slope and Intercept Coefficient Histograms for 6 Samples

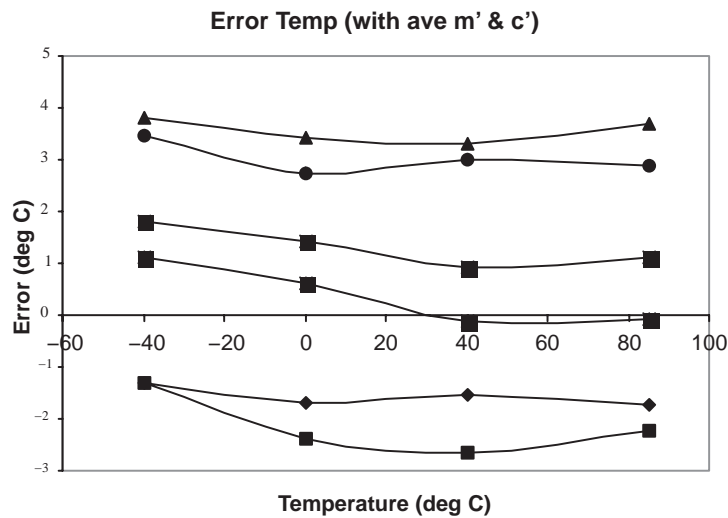


Figure 6. Temperature Measurement Error for 6 Samples

In some applications, absolute measurement accuracy is not critical, so measuring the calibration point is eliminated. For those applications that concentrate only on relative temperature change, using the typical coefficient set would be sufficient. However, absolute accuracy is impaired dramatically.

Slope and intercept coefficients of actual devices were acquired for six MSC1210 samples between the temperature of -40 and 85°C at 1MHz CPU clock frequency (clock frequency effects will be discussed later). Figure 5 and Figure 6 show the *Slope and Intercept* chart and the *Temperature Error* for these six sample parts. The average slope (m'_{ave}) and intercept coefficient (c'_{ave}) of the samples are $2582.173^{\circ}\text{C/V}$ and -269.386°C , respectively. The *Slope and Intercept* chart shows the wide variations (5°C : from -273.5 to -269.5°C) of intercept coefficient among all six devices. Each line of the Temperature Error chart shows the measurement error of a sample part. The chart shows that the error value for each part fluctuates below 2°C . These also indicate that the slope variation over the sample devices is low.

If the averaged slope/intercept coefficients are used, temperature measurement error is up to 6.5°C . This error can easily reduce down to 2°C if the intercept coefficient variation is calibrated.

3.3.2 One Point Calibration

One point calibration for a linear equation with two unknown factors requires either the averaged slope or averaged intercept coefficient. As shown in Figure 5, calibrating the intercept coefficient corrects most of the error. When one point calibration is used with the averaged slope coefficient to calculate the intercept coefficient, the error is reduced by more than 4.5°C and reach below 2°C (Figure 4).

3.3.3 Measurement Setups

To minimize self-heating errors, the measurements use a 1MHz clock frequency and 3V power supply.

The curves shown in Figure 5 were acquired when an internal reference voltage is used. Because the temperature stability of the internal reference voltage is trimmed during the device manufacturing process, the slope (gain) coefficient is very stable. The internal reference voltage was able to achieve all the temperature measurement accuracy described in Table 3.

4 Calibration Setups

4.1 Reference Sensor

This report uses an RTD temperature sensor to calibrate the MSC121x measurements. YSI Precision Temperature Group manufactures the RTD sensor, model 55031 [3]. The measurement accuracy is trimmed to within 0.05°C . The RTD resistance to temperature relationship is shown in Equation 6.

$$T = (a + b \ln(R) + c \ln(R)^3)^{-1}$$

Equation 6. RTD Resistance to Temperature

R is in ohms, a/b/c are constants, and T is in °Kelvin. Equation 6 coefficients are measurement temperature range dependent. A different set of a, b, and c are used for a specified range of temperature. Once the sensing temperature range is defined, these factors are constant. YSI provided an Excel file to calculate the coefficients.

$\partial R/\partial T$ (Ω per °C) defines the requirement of measurement accuracy. For example, at 25°C, $\partial R/\partial T = -99 \Omega/^\circ\text{C}$, R is around 2.2k Ω . To measure 0.05°C, a DMM needs to have resolution of 5- Ω (99×0.05) for the range setting for 2k Ω . The $\partial R/\partial T$ values for different temperatures are supplied with the YSI attached Excel file.

4.2 Reference Sensor Measurements

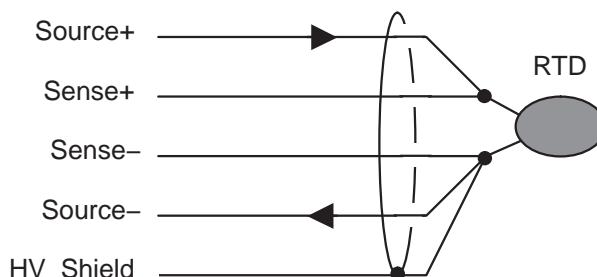


Figure 7. RTD 5 Wires Configuration

An HP3458A Digital Multimeter is used in this report to measure the RTD resistance. Figure 7 shows the 5 wires connection used for RTD resistance measurement the meter supports. (Sense+, Sense-) connection pair is for RTD voltage sensing inputs. This pair carries almost zero current to avoid measuring any voltage drop caused by lead connections resistance. (Source+, Source-) connection pair is for excitation current for resistance measurement. The current from the meter is less than 100 μA to minimize the RTD self-heating effect caused by I-R drop. This meter is able to measure better than 0.05°C over the RTD resistance range within its corresponding temperature. The HV Shield connection (Figure 7) protects the measurement from noise interference and external high voltage discharge.

4.3 Temperature Bath

A stable temperature bath helps to reduce both the self-heating effect and the temperature gradient caused by the device package, and provides a constant temperature for calibration. The self-heating effect will be discussed in Section 5. H-Galden ZT 180 [4], a heat transfer fluid, is used in the bath. It is a non-electric-conducting, thermally- and chemically-stable fluid. To increase the effectiveness of the bath, a 1A stirring fan with a PWM speed control circuit is used to break the H-Galden fluid ventilation, and to maintain constant temperature over the bath. The temperature bath is placed inside a programmable oven to perform calibration.

4.4 Package Junction Temperature

The MSC121x device is packaged in a 64-lead TQFP package. This package has junction-to-case thermal resistance (θ_{JC}) of $4.3^{\circ}\text{C}/\text{W}$. This application controls MSC121x power dissipation within 3.6mW ($3\text{V} \times 1.2\text{mA}$ at 1.8MHz). This power dissipation introduces a mere 0.015°C ($3.6\text{mW} \times 4.3^{\circ}\text{C} / \text{W}$) of temperature gradient between the silicon die and the temperature bath fluid, which is removed by the temperature calibration process. High device power dissipation should be avoided for precise temperature measurement.

5 Self-Heating Effect

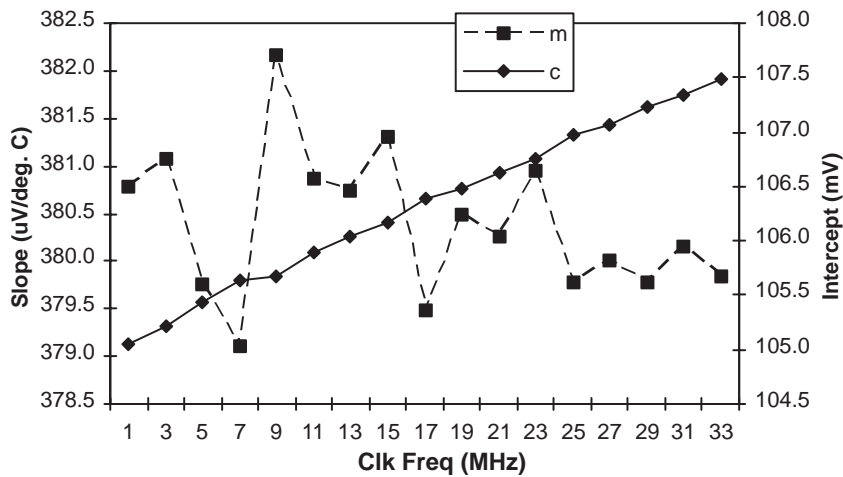


Figure 8. Heating Effect from Clock Frequency Change

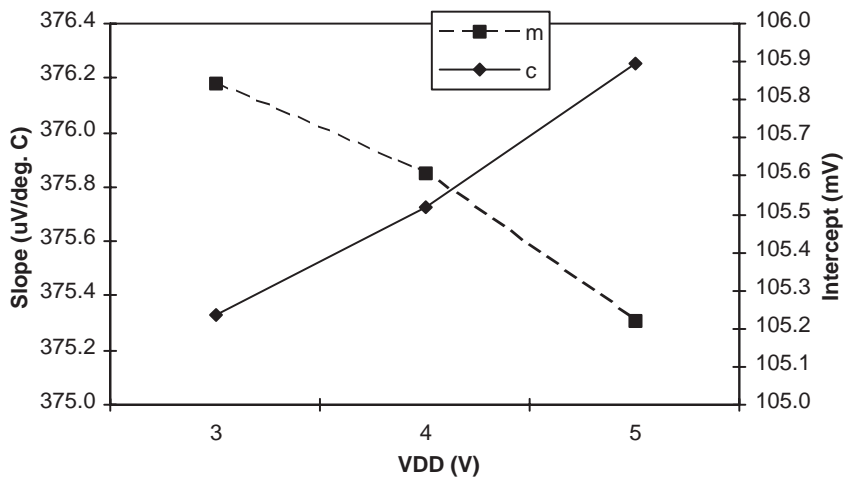


Figure 9. Self-Heating Effect from Power Supply Voltage Change

Heat generated by sensors when power is applied causes self-heating. When the MSC121x operates as a temperature sensor, the applying power introduces self-heating and affects the calibration coefficient. The device heat dissipation is proportional to the power supply voltage, operation frequency, and on-chip operating features. Figure 8 and Figure 9 show the self-heating effect on slope and intercept coefficients when the device operation frequency or supply voltage is increased. If the coefficients are calibrated, the self-heating effect is removed with the calibration process. However, if the coefficients are not calibrated, or the application environment is very different from the environment when the coefficients are prepared, minimum heat dissipation from the device is preferred. Minimum heat dissipation requires a lower power supply voltage and clock frequency. The lowest heat dissipation condition recommended for the MSC121x is 1 MHz clock frequency with 3V power supply.

6 Example Code

The MSC1210-DAQ-EVM [5] board is used for running the example code. Raisonance IDE is used for the code development. The clock frequency is running at 1.8432MHz. The power supply is at 3V. Appendix B lists the source code, using floating-point math. The size of the code is 3kB, which is supported by the Raisonance 4kB Demo Version.

To minimize power consumption, unused peripherals are shut off. The PSEN and ALE pins are also turned off.

```
PDCON &= 0x0f7;           //turn on adc
PASEL=0xff;
```

List 1 . Power Control

ADC is set to convert at 7SPS. Since the DAQ-EVM used is calibrated, temperature drift error is canceled by the calibration. Instead of using an external reference voltage, the internal reference is used.

```
ACLK=1;                   // ACLK = 1.8432MHz/(1+1)= 0.9216MHz
DECIMATION = 0x7ff;
ADCON0 = 0x20;           // Vref on 1.25V, Buff off, BOD off, PGA 1
ADMUX=0xff;
ADCON1 = 0x01;          // bipolar, auto, self calibration, offset, gain
```

List 2 . ADC Setup

The on-chip summation register is used. The 7 SPS conversion is further averaged by 32 times.

```
SSCON=0;                 // Clear SUMR0~3
SSCON=0xe4;             // Set SSCON for ADC 32 summations and div by 32
```

List 3 . On-chip summation register setup

In order to achieve resolution higher than 0.01°C, a moving-window of size 32 is used. The linear and polynomial equations are calculated with 32-bit floating point math.

```
tc_lin=M0*vt + C0;  
tc_poly=A1*vt*vt + B1*vt +C1;
```

List 4 . 32-bit floating point math library calculates the linear and polynomial equations

To minimize code memory usage, a recursive routine *print* is added instead of the library *printf*. *printf* with a floating point requires over 1kB additional memory, while *print* and its calling routine need only 234 bytes.

References

- [1] *MSC1210/MS1211/MS1212 Product Data Sheets* (SBAS203A, SBAS267, SBAS278)
- [2] *Measuring Temperature with the ADS1210, ADS1217, or ADS1218* (SBAA073)
- [3] *YSI Precision Temperature Group* <http://www.ysi.com>
- [4] *Solvay Solexis*: http://www.solvaysolexis.com/pdf/h_gald_zt180.pdf
- [5] *MSC1210-DAQ-EVM User's Guide and Examples* (SBAU083)

Appendix A. Sample Part Measurement Data

Temperature (°C)	V _{temp} (mV)	Linear Error	Poly Error
-44.36	87.92666435	0.438626575	0.044972785
-39.6	89.71338287	0.251329446	-0.047687135
-30.07	93.35722938	0.121571235	-0.006194279
-19.54	97.39257813	-0.019675812	0.008144526
-9.34	101.3098907	-0.142078513	0.002530738
0.67	105.1522636	-0.249363725	-0.022975509
11.18	109.215641	-0.269842725	0.00771484
21.39	113.1717587	-0.263136332	0.029364017
31.01	116.8513966	-0.300837209	-0.025324675
40.77	120.6834221	-0.191998502	0.034180009
50.58	124.5174599	-0.158498335	-0.013989796
60.31	128.3015156	-0.063606864	-0.031392908
70.94	132.4857807	0.155197957	0.026589074
80.18	136.1010933	0.297174865	-0.001386513
85.01	138.0062601	0.39513794	-0.004545181

Table A-1. Sample Part Measurement Data

Appendix B. Temperature.c Source Listing

```

#include <REG1210.H>
#include <stdlib.h>
#include <math.h>
// Vref=1.25V, bipolar results give 1.25*2/2^24
#define LSB      (1.25/8388608)
#define M0      2586.67098545498
#define C0      -271.7529
#define A1      -1.08436244851484e3
#define B1      2.83158996601634e3
#define C1      -285.1293
#define WINDOWSIZE 16
signed long summer(void);
extern void putspace4(void);
extern void tx_byte(char);
// Print a message
void putstr(char code * data msg)
{
    while (*msg != 0) {
        tx_byte((unsigned char) *msg);
        if( *msg=='\n') tx_byte('\r');
        msg++;
    }
}
// recursive digit display routine
void prt_digit(unsigned long int i, signed char d) reentrant
{
    unsigned long int j; char c;
    j=i/10; c=i-j*10; d--;
    if (j!=0 || !(d &0x80)) prt_digit(j,d);
    if (d==0) tx_byte('.');
    tx_byte(c+48);
}
// Display long integer number with sign and decimal
void print(signed long int i, unsigned char d)
{
    if (i<0) { tx_byte('-'); i*=-1;}
    prt_digit(i,d); putspace4();
}
void main(void)
{
    signed long int data sum;
    float data window[16]={0,0,0,0, 0,0,0,0, 0,0,0,0, 0,0,0,0};
    float data adres=0, vt, tc_lin, tc_poly;
    unsigned char fill_ptr=1, mod_ptr=0;
    T2CON = 0x34; // T2 as baudrate generator
    RCAP2 = 65535; // 57600 Baud @ 1.8432MHz
    SCON = 0x52; // Async mode 1, 8-bit UART, enable rcvr, TI=1, RI=0
    putstr("\x1b[1;33;46m\x1b[2J\x1b[12CTemperature Sensor\n");
    PDCON &= 0x0f7; //turn on adc
    PASEL=0xff;
    ACLK=1; // ACLK = 1.8432MHz/(1+1)= 0.9216MHz
    DECIMATION = 0x7ff;
    ADCON0 = 0x20; // Vref on 1.25V, Buff off, BOD off, PGA 1
    ADMUX=0xff;
    ADCON1 = 0x01; // bipolar, auto, self calibration, offset, gain
    SSCON=0; // Clear SUMR0~3
    SSCON=0xe4; // Set SSCON for ADC 32 summations and div by 32
    sum=summer(); // Discard 1st summation result
}

```

```

SSCON=0;                // Clear SUMR0~3
SSCON=0xe4;            // Set SSCON for ADC 32 summations and div by 32
while(1){
    sum=summer();
    SSCON=0;            // Clear SUMR0~3
    SSCON=0xe4;        // Set SSCON for ADC 32 summations and div by 32
    adres=adres-window[mod_ptr];    // Moving Window of 10 results
    window[mod_ptr]=(float) sum;
    adres=adres+ window[mod_ptr];
    vt=adres/(float)fill_ptr*LSB;
    tc_lin=M0*vt + C0;
    print((signed long int)(tc_lin*1000),3);
    tc_poly=A1*vt*vt + B1*vt +C1;
    print((signed long int)(tc_poly*1000),3);
    if (fill_ptr==WINDOWSIZE) fill_ptr=WINDOWSIZE; else fill_ptr++;
    if (mod_ptr==(WINDOWSIZE-1)) mod_ptr=0; else mod_ptr++;
    putstr("\n");
    if (RI==1){ // Any key will pause, any key again to start
        putstr("Pause....");
        RI=0;
        while(RI==0) {;}
        putstr("Continue\n");
        RI=0;
    }
}
}
}

```

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